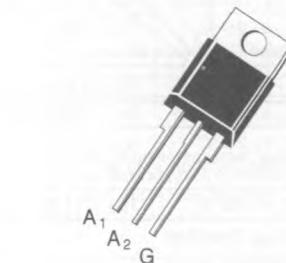


TRIACS

- GLASS PASSIVATED CHIP
- EXCELLENT $(dv/dt)_c > 10 \text{ V}/\mu\text{s}$
- I_G SPECIFIED IN FOUR QUADRANTS
- AVAILABLE IN INSULATED VERSION → BTA SERIES (INSULATING VOLTAGE 2500 V_{RMS}) OR IN UNINSULATED VERSION → BTB SERIES
- UL RECOGNIZED FOR BTA SERIES (E81734)


TO 220 AB
(Plastic)

DESCRIPTION

New range suited for applications such as phase control and static switching.

ABSOLUTE RATINGS (limiting values)

Symbol	Parameter	Value	Unit
I _{T(RMS)}	RMS on-state Current (360° conduction angle)	75 °C	A
I _{TSM}	Non Repetitive Surge Peak on-state Current (T _j initial = 25 °C - Half sine wave)	t = 8.3 ms	A
		t = 10 ms	
I ² t	I ² t Value for Fusing	t = 10 ms	A ² s
di/dt	Critical Rate of Rise of on-state Current (1)	Repetitive F = 50 Hz	A/μs
		Non Repetitive	
T _{stg} T _j	Storage and Operating Junction Temperature Range	- 40 to 150	°C
		- 40 to 110	°C

Symbol	Parameter	BTA/BTB 08-					Unit
		200B	400B	600B	700B	800B	
V _{DRM}	Repetitive Peak off-state Voltage (2)	200	400	600	700	800	V

(1) I_G = 1 A di/dt = 1 A/μs

(2) T_j = 110 °C.

THERMAL RESISTANCES

Symbol	Parameter	Value	Unit
R _{th (j-a)}	Junction to Ambient	60	°C/W
R _{th (j-c) DC}	Junction to Case for DC	4.3	°C/W
R _{th (j-c) AC}	Junction to Case for 360° Conduction Angle (F = 50 Hz)	3.2	°C/W

GATE CHARACTERISTICS (maximum values)

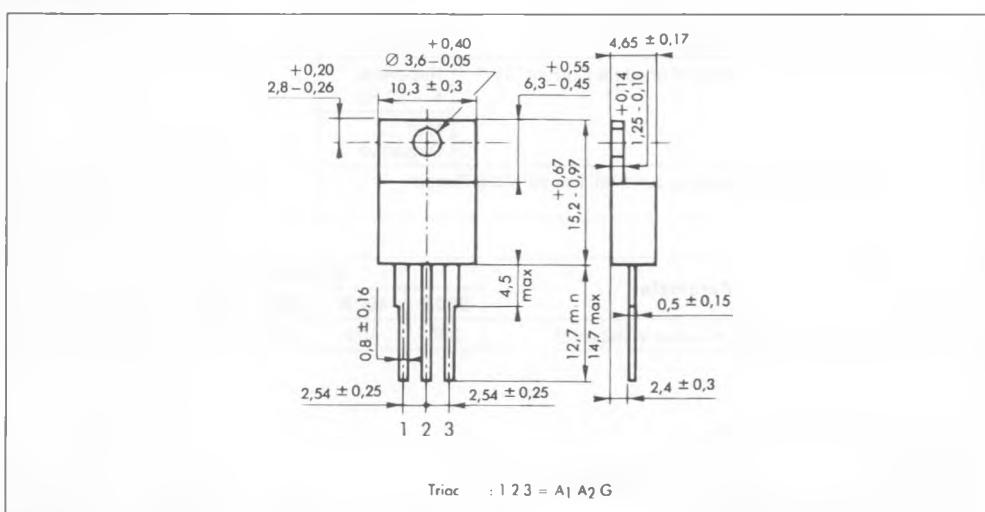
$$\begin{array}{ll} P_{GM} = 40 \text{ W } (t_p = 10 \mu\text{s}) & I_{GM} = 4 \text{ A } (t_p = 10 \mu\text{s}) \\ P_{G(AV)} = 1 \text{ W } & V_{GM} = 16 \text{ V } (t_p = 10 \mu\text{s}) \end{array}$$

ELECTRICAL CHARACTERISTICS

Symbol	Test Conditions			Quadrants	Min.	Typ.	Max.	Unit
I_{GT}	$T_j = 25^\circ\text{C}$ $V_D = 12 \text{ V}$ $R_L = 33 \Omega$ Pulse Duration > 20 μs			I-II-III			50	mA
				IV			100	
V_{GT}	$T_j = 25^\circ\text{C}$	$V_D = 12 \text{ V}$	$R_L = 33 \Omega$	I-II-III-IV			1.5	V
V_{GD}	$T_j = 110^\circ\text{C}$	$V_D = V_{DRM}$	$R_L = 3.3 \text{ k}\Omega$	I-II-III-IV	0.2			V
I_H^*	$T_j = 25^\circ\text{C}$	$I_T = 100 \text{ mA}$	Gate Open				50	mA
I_L	$T_j = 25^\circ\text{C}$ $V_D = 12 \text{ V}$ $I_G = 200 \text{ mA}$ Pulse Duration > 20 μs			I-III-IV		50		mA
				II		100		
V_{TM}^*	$T_j = 25^\circ\text{C}$	$I_{TM} = 11 \text{ A}$	$t_p = 10 \text{ ms}$				1.75	V
I_{DRM}^*	V_{DRM} Specified		$T_j = 25^\circ\text{C}$				0.01	mA
			$T_j = 110^\circ\text{C}$				0.5	
dv/dt^*	$T_j = 110^\circ\text{C}$ Gate Open Linear Slope up to $V_D = 67\% V_{DRM}$				250	500		V/ μs
$(dv/dt)_c^*$	$T_C = 75^\circ\text{C}$	$V_D = V_{DRM}$	$I_T = 11 \text{ A}$		10			V/ μs
t_{gt}	$T_j = 25^\circ\text{C}$	$V_D = V_{DRM}$	$I_T = 11 \text{ A}$	I-II-III-IV		2		μs
* For either polarity of electrode A ₂ voltage with reference to electrode A ₁ .								

PACKAGE MECHANICAL DATA

TO 220 AB Plastic



Cooling method : by conduction (method C)

Marking : type number

Weight : 2 g.

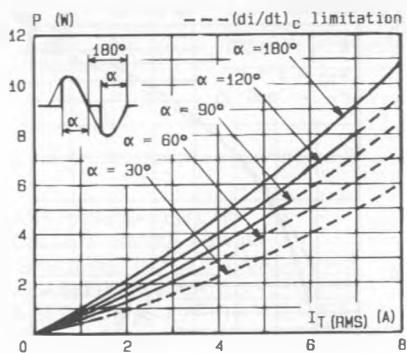


Fig.1 - Maximum mean power dissipation versus RMS on-state current ($F = 60$ Hz).

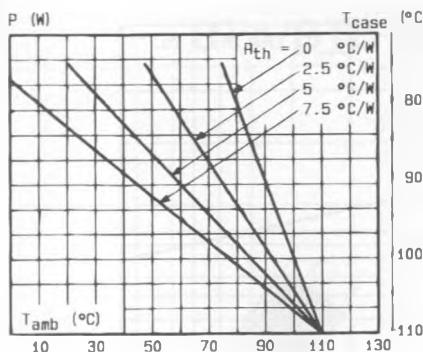


Fig.2 - Correlation between maximum mean power dissipation and maximum allowable temperatures (T_{amb} and T_{case}) for different thermal resistances heatsink + contact.

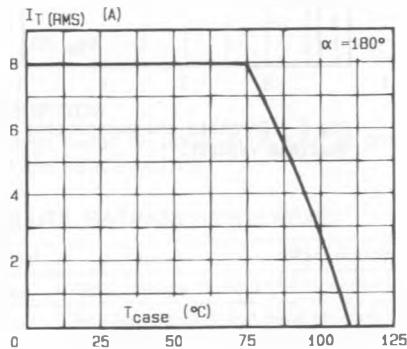


Fig.3 - RMS on-state current versus case temperature.

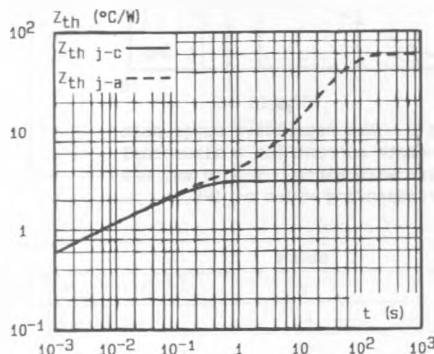


Fig.4 - Thermal transient impedance junction to case and junction to ambient versus pulse duration.

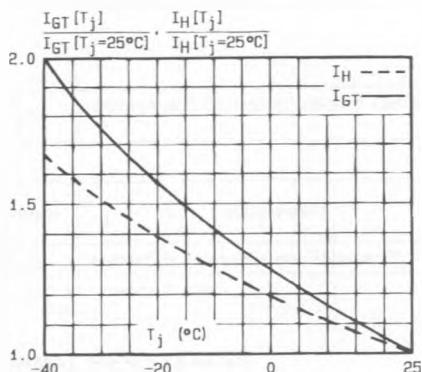


Fig.5 - Relative variation of gate trigger current and holding current versus junction temperature.

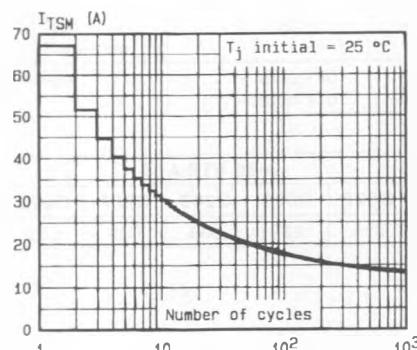


Fig.6 - Non repetitive surge peak on-state current versus number of cycles.

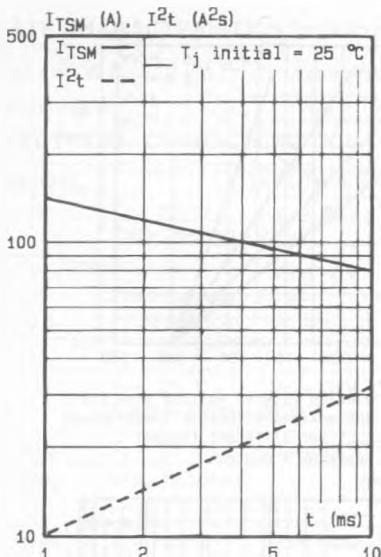


Fig.7 - Non repetitive surge peak on-state current for a sinusoidal pulse with width : $t \leq 10$ ms, and corresponding value of I^2t .

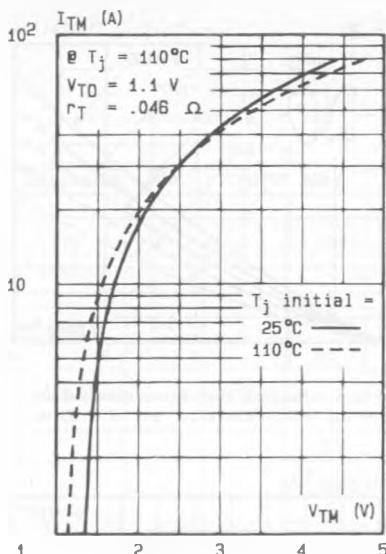


Fig.8 - On-state characteristics (maximum values)